

Notice of References Cited	Application/Control No. 10/071,172	Applicant(s)/Patent Under Reexamination VAANANEN ET AL.	
	Examiner Kieu D Vu	Art Unit 2173	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,577,296	06-2003	Flack, James F.	345/158
	B	US-6,466,198	10-2002	Feinstein, David Y.	345/158
	C	US-6,201,554	03-2001	Lands, Robert M.	345/169
	D	US-5,602,566	02-1997	Motosyuku et al.	345/684
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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